Electrical/Optical Issues in I/O CMOS Interfaces

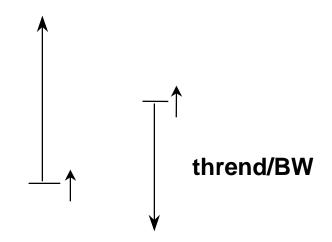
Thad Gabara
Bell Laboratories
Murray Hill, NJ



Electrical vs. Optical

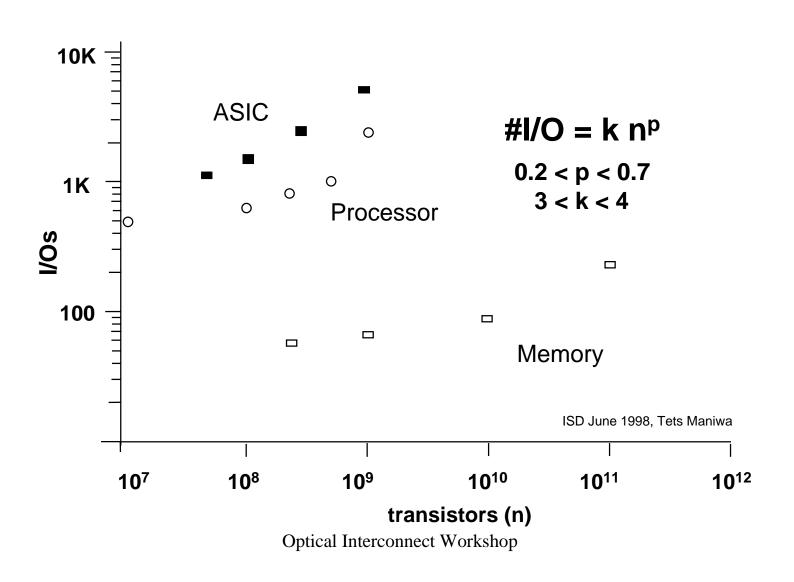
Interconnect length is a limiting aspect

on-chip
between chips
between boards
between cabinets
between buildings
cities and countries

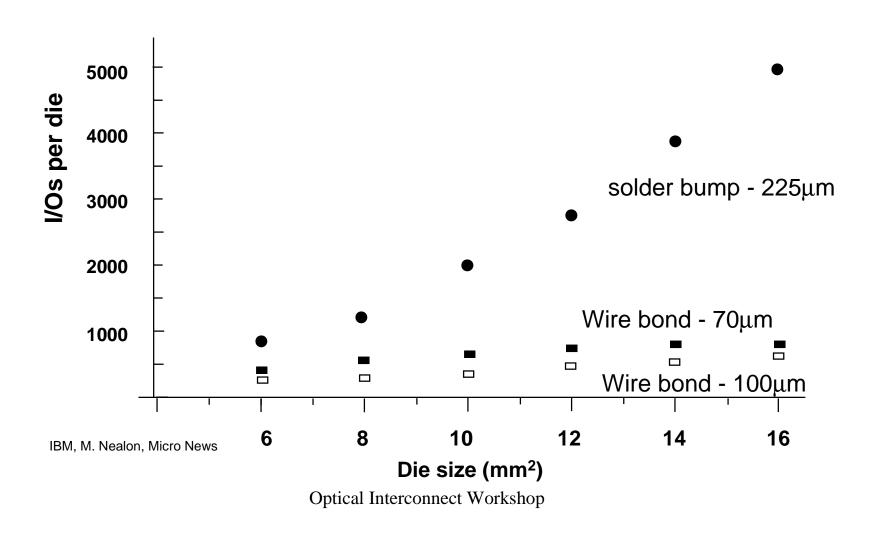


Electrical Optical

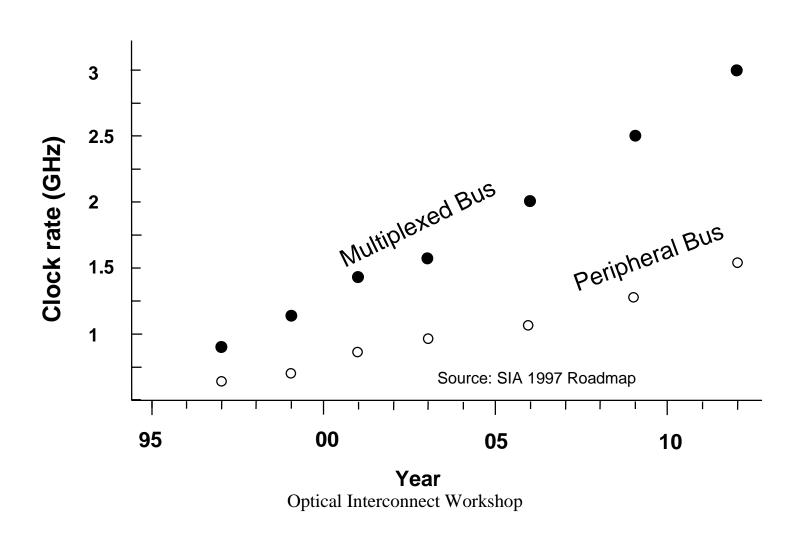
Rent's Rule



Chip Interconnect Density



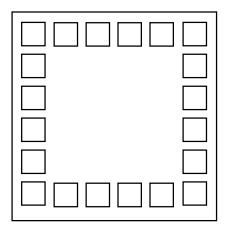
Chip to Board Clock Rate

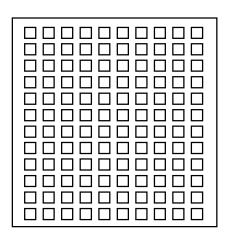


I/O Impact of Scaling CMOS

- Density in core is increasing
- Allows more data to be processed
- Need to keep up information transfer to/from core
- I/O transfer rates increasing
- Rent's rule forces high pin count

Chip I/O Limitation



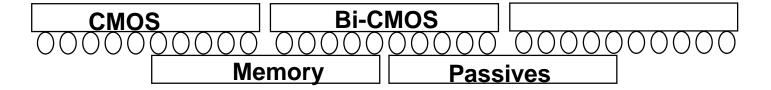


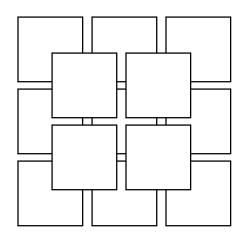
Wire bond

Solder bump

Solder bump
 Process and packaging step differences
 CAD tools for chip partitioning
 Offers new potentials for system growth
 Allows for optimized process attachment

Solder Bump System Possibilities

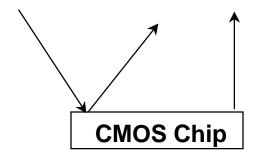


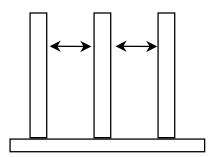


 Shingling die Combine different optimized die together Allows formation of compact systems

Optical Chip Communication

- Process added step to CMOS
- SEED, VCSEL needs to cost compete with solder bump
- May offer backplane benefits
- Current High BW interfaces may benefit CPU-memory Switching networks

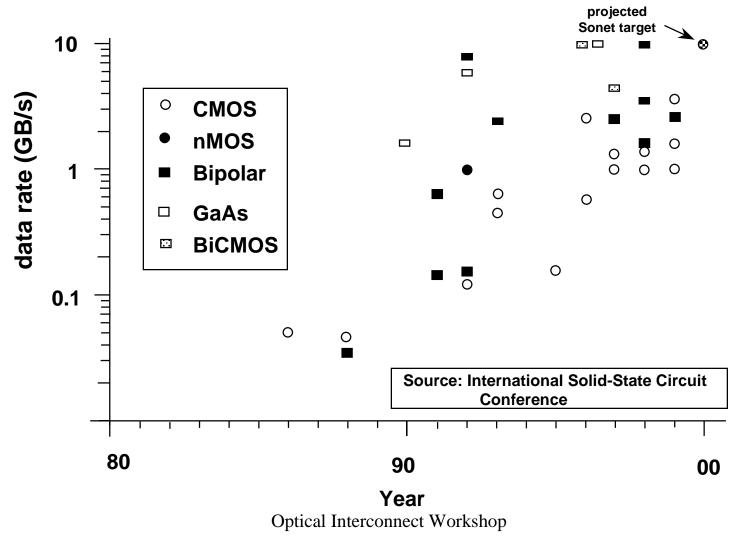




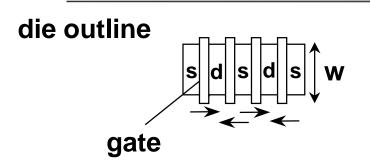
CDR Background

- single interconnect
 - coding schemes
 - contains both clock and data
 - bandwidth efficient connection
- at destination
 - perform post-processing to extract clock from data
- synchronize data at destination
 - using recovered clock

Clock and Data Recovery Performance Trend



Shadowing

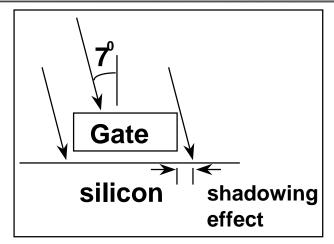


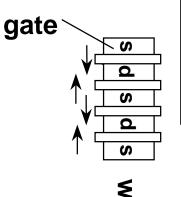
- Digital ASIC technique
- Use same layout around the frame
- Typically use a linear layout
- Small swing buffers are a problem

Measured Data of V_{ol} of 800mV swing(over several lots)

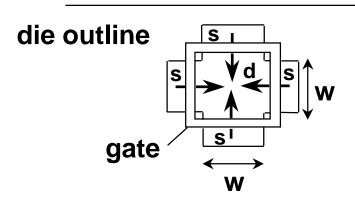
linear

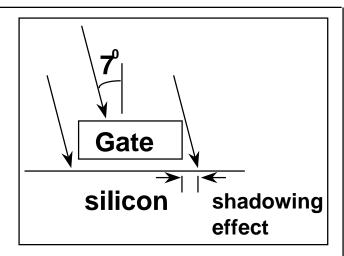
Avg Δ**V** σ 136mV 31.6mV





Rotational Symmetry

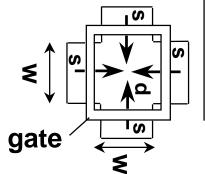




- Current matches
- Gate segments match

Measured Data of V_{ol} of 800mV swing(over several lots)

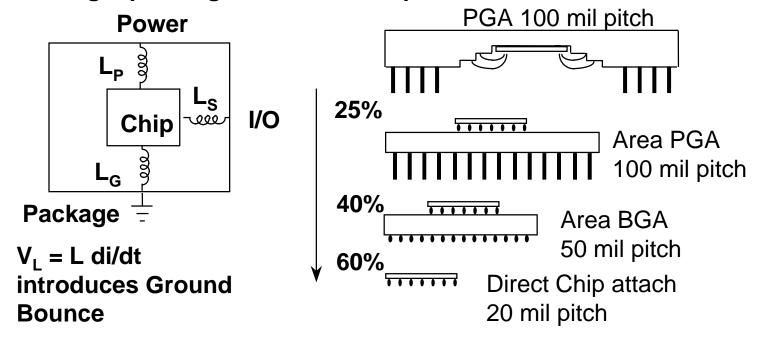
linear Rot Sym Avg ΔV σ 136mV 31.6mV 30mV 8.9mV



Optical Interconnect Workshop

Packaging

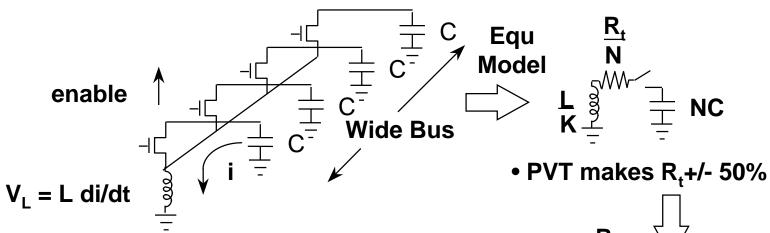
Need to get power/ground to the chip



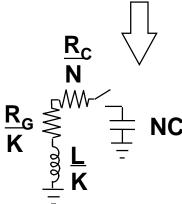
IBM, M. Nealon, Micro News

Package size reduction achieves: Lower L; smaller board area.

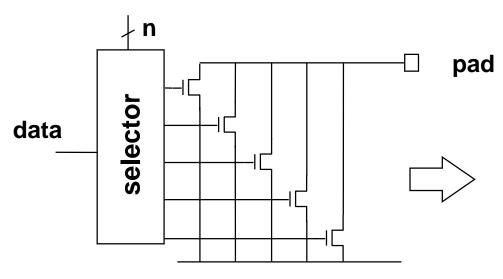
Ground Bounce Reduction



- Want to dampen the circuit
- Use transistor sizing to control transistor impedance - R_c
- Insert impedance in VSS pad and inverse regulate ground impedance - R_G

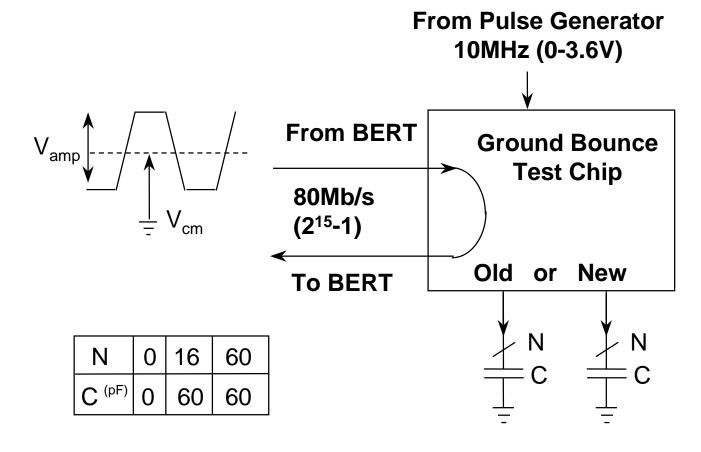


Digital Transistor Sizing

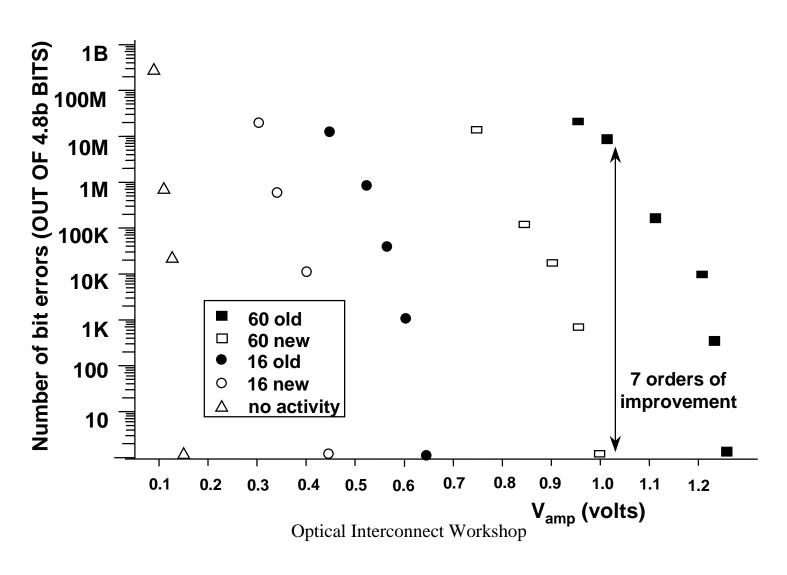


- Technique used over 2Gb/s
- Data path segregated from control
- Selector allows dynamic transistor sizing
- PVT (Process, Voltage, Temp) compensated (R and I)
- Controls impedance, performance, power, etc.
- Used in Ground Bounce buffers, HSTL and other buffers

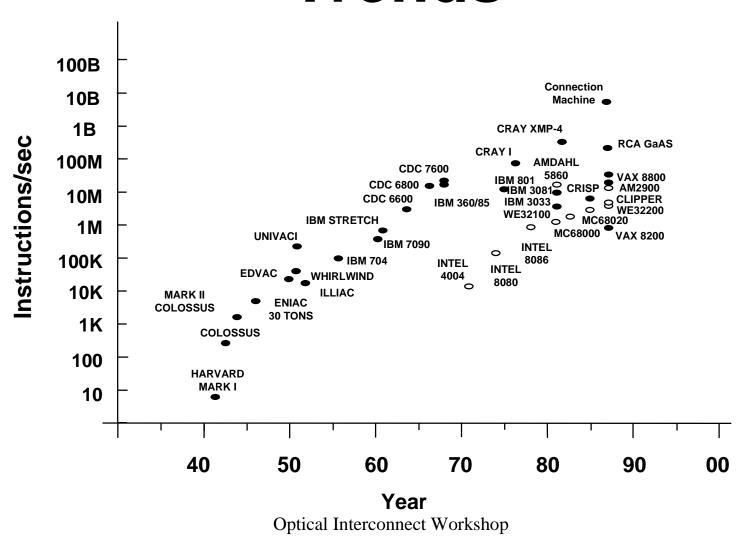
Test Setup to Measure Bit Errors



Bit Errors Generated

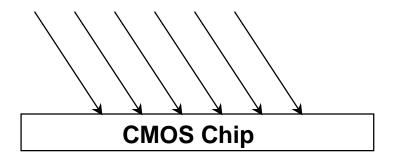


Computer/µProcessor Trends



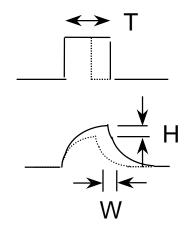
Optical Chip Clocking

- Process added step to CMOS maybe?
- Reduces skew
- Easier to synchronize chip

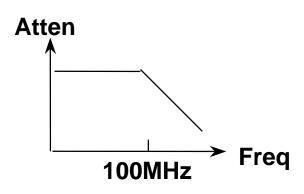


Skin Effect

- Skin effect $\delta = (\pi f \mu \sigma)^{-0.5}$
- Affects the cross-sectional area
- The high-frequency components become more attenuated
- This causes "pattern dependent" effects which is know as intersysmbol interference



Below some T, the eye diagram of the data degrades in W and H

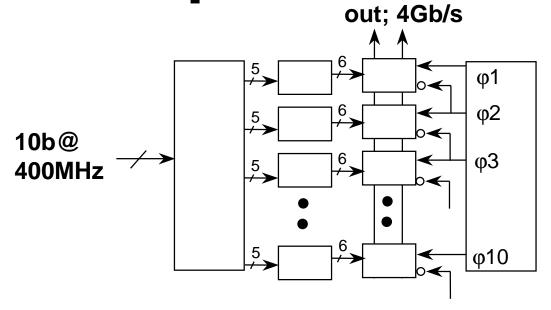


Optical Interconnect Workshop

Optical Communication

- Skin effect doesn't occur
- Attenuation 0.2db/km?
- Electrical attenuation -5db at a few GHz
- Electrical intersysmbol interference gone
- This is nice
- Circuits and techniques push the envelope
- ULSI gives transistors to use for I/O

Equalization



Distribute filter DAC Clock

- Pre-emphasizes signal to compensate for attenuation
- Gives flat attenuation response from 0.2 to 2GHz
- 4Gb/s over 100m

Conclusions

- Reviewed the SIA roadmap for I/O
- I/O Impact of scaling CMOS
- Circuit and system techniques
- Skin effect
- Equalization
- CMOS circuit design, infrastructure, CAD tools, ULSI, all favor pushing existing limits
- Tends to delay optical entry at the lowest level